Supporting Information

for

*Advanced Materials*, adma.200602851

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69451 Weinheim, Germany
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Template/VUV-assisted Fabrication of Ag Nanoparticle Array on Flexible and Rigid Substrates

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Figure S1. (Upper) AFM cross-sectional phase image of the as-annealed diblock copolymer film PEO272-b-PMA(Az)102 on Si wafer. (Bottom) Schematic illustration of the mapping of copolymer film’s cross-section. (This AFM characterization of the cross-section of polymer thin film on solid substrate has been recently developed in the authors’ laboratory and the detailed measurement will be reported elsewhere.)
**Figure S2.** AFM height and phase images of AgNO₃ loaded diblock copolymer PEO₂₇₂-b-PMA(Az)₁₀₂ film on Si wafer. Insets are the corresponding FFT images.

**Figure S3.** FE-SEM image of PEO₂₇₂-b-PMA(Az)₁₀₂ templated Ag nanoparticle array on PET, which was obtained after VUV irradiation of AgNO₃ loaded copolymer film for 30 min.
Figure S4. AFM height image of $\text{PEO}_{272-b}$-$\text{PMA(Az)}_{102}$ templated Ag nanoparticle arrays on PET, which was obtained after VUV irradiation of $\text{AgNO}_3$ loaded copolymer film for 30 min.